

# Resource Summary Report

Generated by [dkNET](#) on Jul 29, 2026

## FEI: Meridian 7 System for Semiconductors

RRID:SCR\_019888

Type: Tool

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### Proper Citation

FEI: Meridian 7 System for Semiconductors (RRID:SCR\_019888)

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### Resource Information

**URL:** <https://www.fei.com/products/efa/Meridian-7-for-Semiconductors/>

**Proper Citation:** FEI: Meridian 7 System for Semiconductors (RRID:SCR\_019888)

**Description:** Electrical failure analysis system for semiconductors that provides visible laser voltage imaging and probing and dynamic laser stimulation on sub-10nm devices.

**Resource Type:** instrument resource

**Keywords:** FEI, EFA System, Instrument Equipment, USEDit,

**Availability:** Commercially available

**Resource Name:** FEI: Meridian 7 System for Semiconductors

**Resource ID:** SCR\_019888

**Alternate IDs:** Model\_Number\_Meridian\_7

**Record Creation Time:** 20220129T080347+0000

**Record Last Update:** 20260725T190918+0000

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### Ratings and Alerts

No rating or validation information has been found for FEI: Meridian 7 System for Semiconductors.

No alerts have been found for FEI: Meridian 7 System for Semiconductors.

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### Data and Source Information

**Source:** [SciCrunch Registry](#)

## Usage and Citation Metrics

We have not found any literature mentions for this resource.